

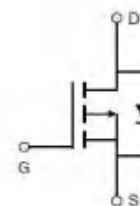
AP60P20Q

P-Channel Enhancement Mosfet



Feature

- -20V,-60A
 $R_{DS(ON)} < 7.0m\Omega @ V_{GS} = -4.5V$
 $R_{DS(ON)} < 9.0m\Omega @ V_{GS} = -2.5V$
- Advanced Trench Technology
- Lead free product is acquired
- Excellent $R_{DS(ON)}$ and Low Gate Charge



Schematic Diagram

Application

- PWM applications
- Load Switch
- Power management



Marking and pin Assignment

Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity (PCS)
60P20Q	AP60P20Q	PDFN3X3	13 inch	-	5000

ABSOLUTE MAXIMUM RATINGS ($T_a = 25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Value	Unit
Drain-Source Voltage	V_{DS}	-20	V
Gate-Source Voltage	V_{GS}	± 12	V
Continuous Drain Current ($T_a = 25^\circ\text{C}$)	I_D	-60	A
Continuous Drain Current ($T_a = 100^\circ\text{C}$)	I_D	-42	A
Pulsed Drain Current ⁽¹⁾	I_{DM}	-240	A
Single Pulsed Avalanche Energy ⁽⁴⁾	E_{AS}	81	mJ
Power Dissipation	P_D	80	W
Thermal Resistance from Junction to Case	$R_{\theta JC}$	1.6	$^\circ\text{C/W}$
Junction Temperature	T_J	150	$^\circ\text{C}$
Storage Temperature	T_{STG}	-55~ +150	$^\circ\text{C}$

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MOSFET ELECTRICAL CHARACTERISTICS($T_a=25^{\circ}\text{C}$ unless otherwise noted)

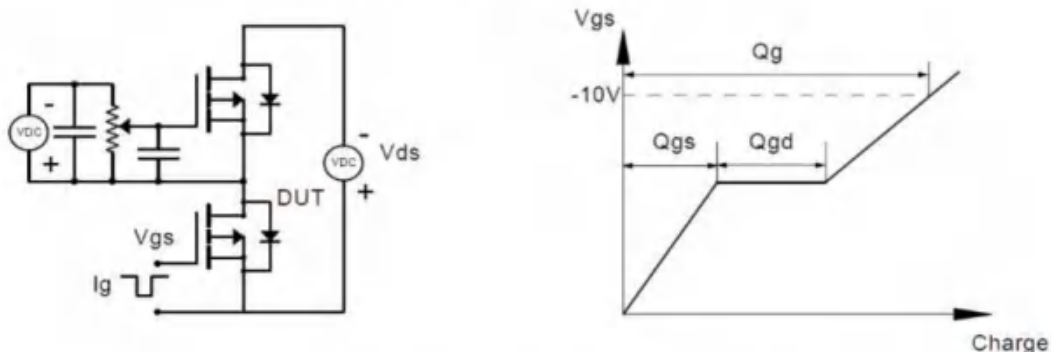
Parameter	Symbol	Test Condition	Min	Type	Max	Unit
Static Characteristics						
Drain-source breakdown voltage	V _{(BR)DSS}	V _{GS} = 0V, I _D =-250μA	-20	-	-	V
Zero gate voltage drain current	I _{DSS}	V _{DS} =-20V, V _{GS} = 0V	-	-	1	μA
Gate-body leakage current	I _{GSS}	V _{GS} =± 12V, V _{DS} = 0V	-	-	±100	nA
Gate threshold voltage ⁽³⁾	V _{GS(th)}	V _{DS} =V _{GS} , I _D =-250μA	0.35	0.6	1.0	V
Drain-source on-resistance ⁽³⁾	R _{DS(on)}	V _{GS} =-4.5V, I _D =-20A	-	5.8	7.0	mΩ
		V _{GS} =-2.5V, I _D =-10A	-	7.0	9.0	
Dynamic characteristics						
Input Capacitance	C _{iss}	V _{DS} =-10V, V _{GS} =0V, f =1MHz	-	7170	-	pF
Output Capacitance	C _{oss}		-	860	-	
Reverse Transfer Capacitance	C _{rss}		-	650	-	
Switching characteristics						
Turn-on delay time	t _{d(on)}	V _{DD} =-10V, I _D =-15A, R _L =0.5Ω V _{GS} =-4.5V, R _G =3Ω	-	20	-	ns
Turn-on rise time	t _r		-	55	-	
Turn-off delay time	t _{d(off)}		-	100	-	
Turn-off fall time	t _f		-	35	-	
Total Gate Charge	Q _g	V _{DS} =-10V, I _D =-20A, V _{GS} =-4.5V	-	63	-	nC
Gate-Source Charge	Q _{gs}		-	10	-	
Gate-Drain Charge	Q _{gd}		-	18	-	
Source-Drain Diode characteristics						
Diode Forward voltage ⁽²⁾	V _{DS}	V _{GS} =0V, I _S =-20A	-	-	-1.2	V
Diode Forward current ⁽³⁾	I _S		-	-	-60	A

Notes:

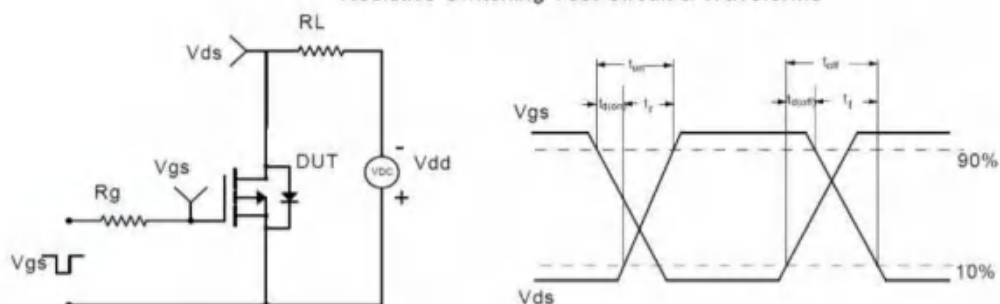
1. Repetitive Rating: pulse width limited by maximum junction temperature
2. Pulse Test: pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$
3. Surface Mounted on FR4 Board, $t \leq 10$ sec
4. EAS Condition: $T_J = 25^{\circ}\text{C}$, $V_{DD} = -10V$, $R_G = 25\Omega$, $L = 0.5mH$

Test Circuit

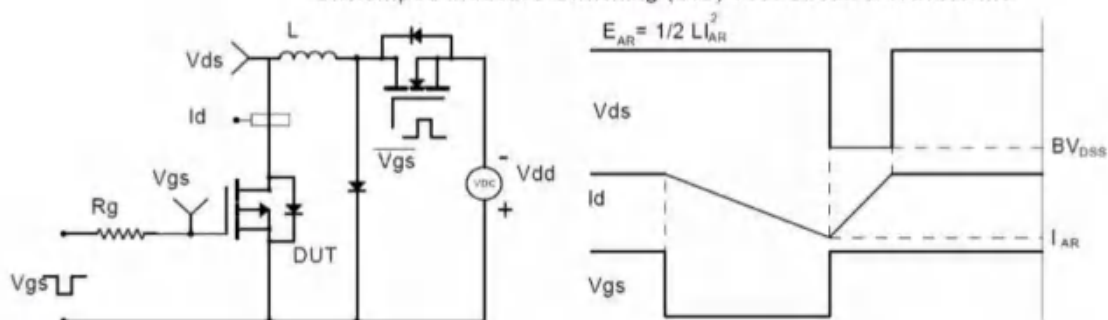
Gate Charge Test Circuit & Waveform



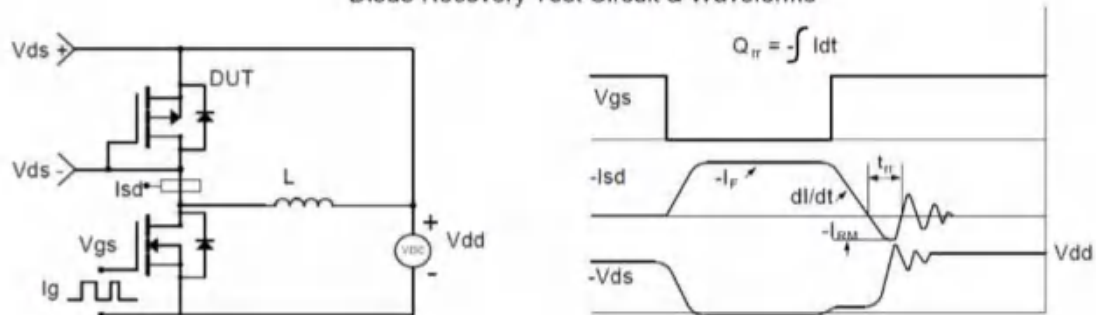
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



Typical Performance Characteristics

Figure1: Output Characteristics

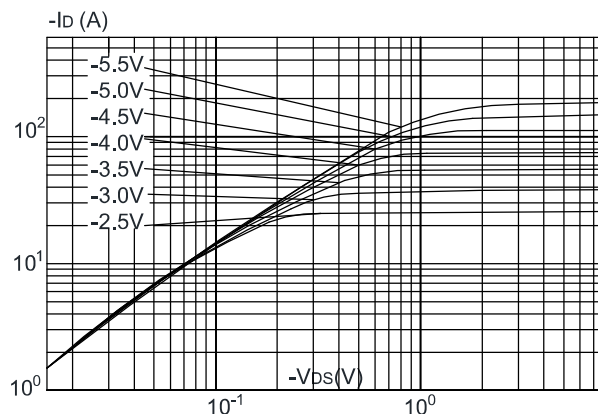


Figure 2: Typical Transfer Characteristics

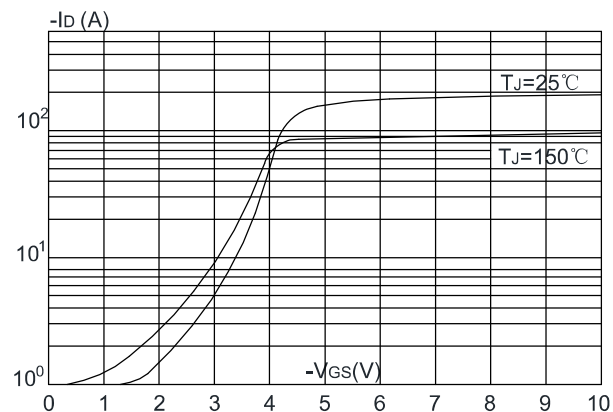


Figure 3: On-resistance vs. Drain Current

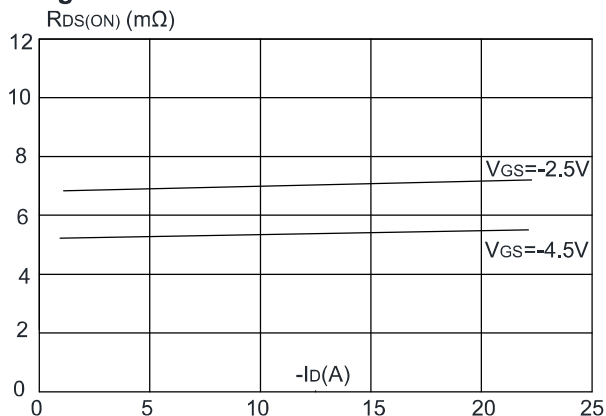


Figure 4: Body Diode Characteristics

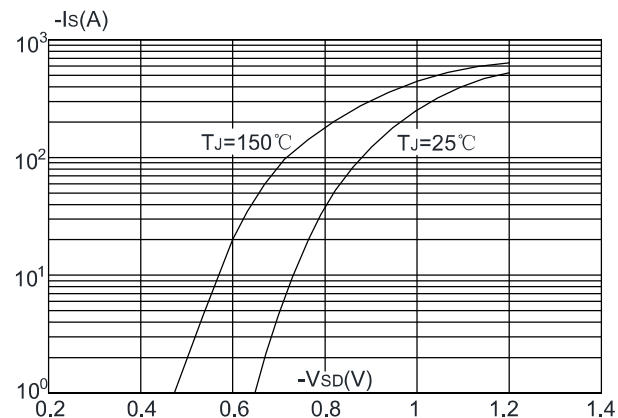


Figure 5: Gate Charge Characteristics

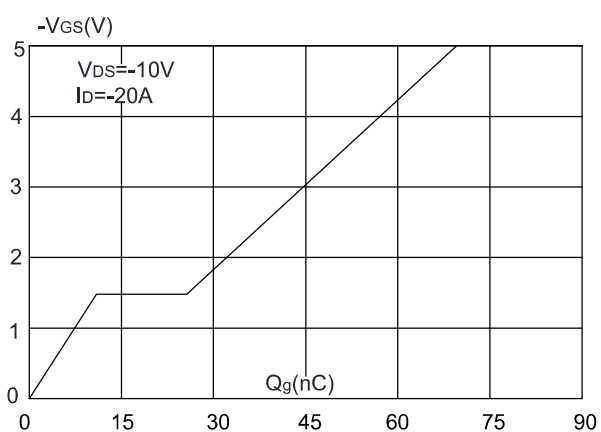
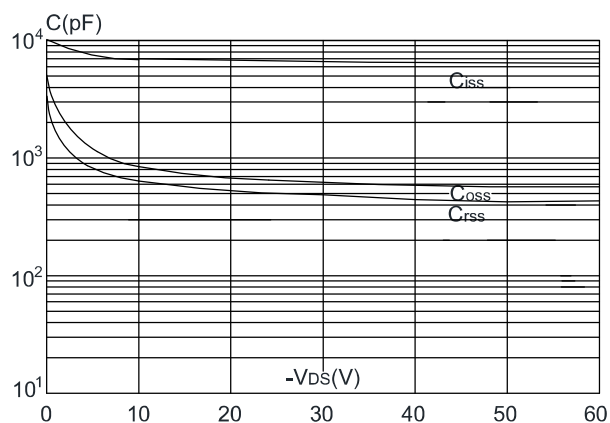


Figure 6: Capacitance Characteristics



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Figure 7: Normalized Breakdown Voltage vs. Junction Temperature

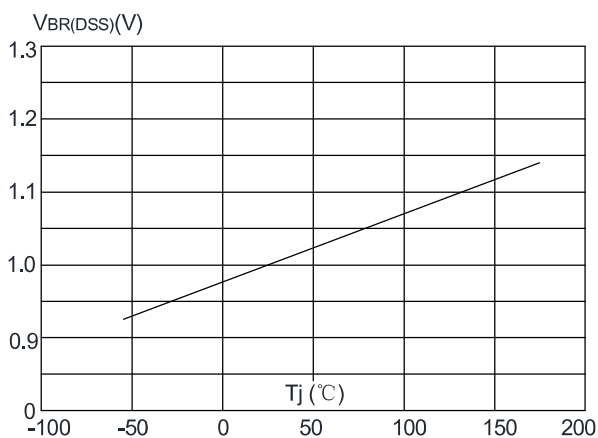


Figure 8: Normalized on Resistance vs. Junction Temperature

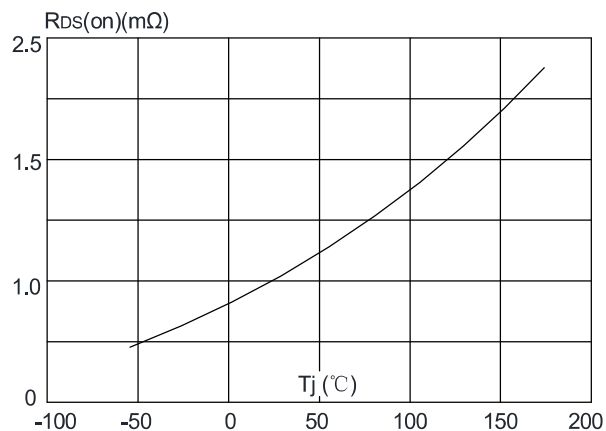


Figure 9: Maximum Safe Operating Area

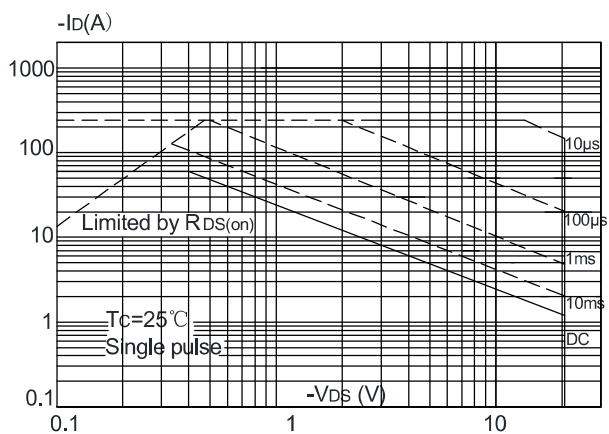


Figure 10: Maximum Continuous Drain Current vs. Case Temperature

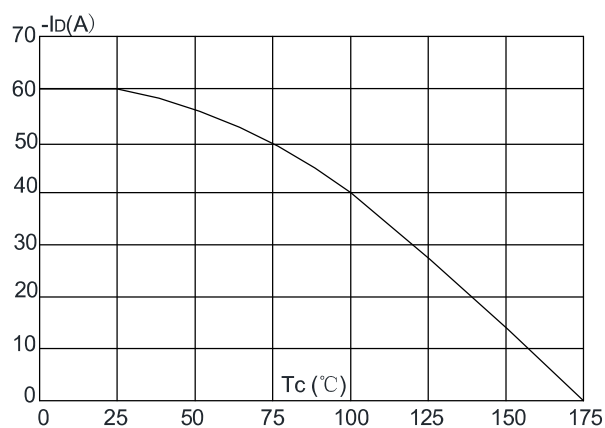
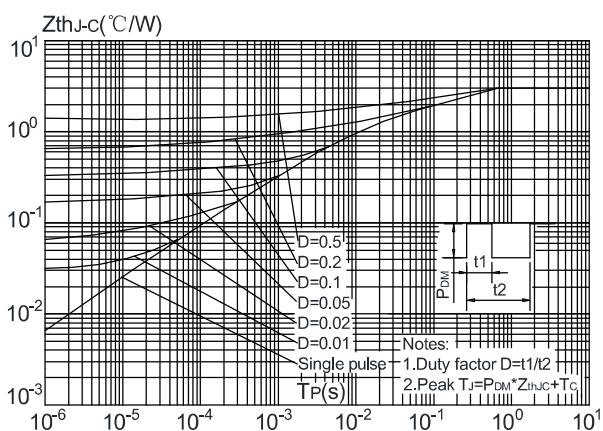


Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Case



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Package Mechanical Data

